

FORM PTO-1449		SERIAL NO. 10/562,175	CASE NO. 13004/3
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		FILING DATE March 2, 2007	GROUP ART UNIT 1645
(use several sheets if necessary)	APPLICANT(S): Peter John Hastwell et al.		CONFIRMATION NO. 1324

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	B1	6,184,608	02/06/2001	Cabuz et al.		
	B2	6,280,595	08/28/2001	Montgomery		
	B3	US2002/0131147 A1	09/19/2002	Paolini et al.		
	B4	US2004/0050701 A1	03/18/2004	McEntee et al.		
	B5	US2004/0055892 A1	03/25/2004	Oh et al.		
	B6	6,855,501	02/15/2005	Huang		

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
	B7	WO 02/034067 A1	04/17/2003	PCT 03/031067		
	B8	WO 03/062456 A1	07/31/2003	PCT		
	B9	WO 01/15800 A1	03/08/2001	PCT		
	B10	WO 02/25936 A2	03/28/2002	PCT		
	B11	JP04/086602	03/19/1992	Japan		Yes

OTHER ART – NON PATENT LITERATURE DOCUMENTS

EXAMINER INITIAL	(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	
	B12	Michael G. Steward et al., "NanoXerography: The Use of Electrostatic Forces to Pattern Nanoparticles", Proceedings of the 2003 NSF Design, Service and Manufacturing Grantees and Research Conference, 7 pgs.

EXAMINER /Chun-Cheng Wang/	DATE CONSIDERED 03/18/2010
-------------------------------	-------------------------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /CCW/